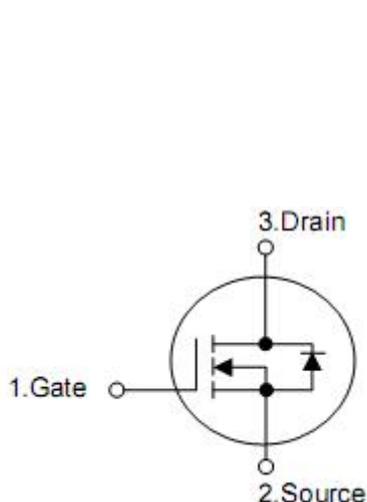


## 1. Features

- n  $V_{DS}=30V, R_{DS(on)}=0.057\Omega @ V_{GS}=10V, I_D=3.5A$
- n  $V_{DS}=30V, R_{DS(on)}=0.094\Omega @ V_{GS}=4.5V, I_D=2.8A$
- n Power MOSFET
- n 100%  $R_g$  tested

## 2. Symbol



Pin	Function
1	Gate
2	Source
3	Drain

## 3. Absolute maximum ratings

( $T_A=25^\circ\text{C}$ , unless otherwise noted)

Parameter	Symbol	Rating	Units
Drain-source voltage	$V_{DS}$	30	V
Gate-source voltage	$V_{GS}$	$\pm 20$	V
Drain current continuous ( $T_J=150^\circ\text{C}$ ) <sup>a, b</sup>	$I_D$	$T_A=25^\circ\text{C}$	3.5
		$T_A=70^\circ\text{C}$	2.8
Pulsed drain current <sup>a</sup>	$I_{DM}$	16	A
Continuous source current (diode conduction) <sup>a, b</sup>	$I_S$	1.25	
Power dissipation <sup>a, b</sup>	$P_D$	$T_A=25^\circ\text{C}$	1.25
		$T_A=70^\circ\text{C}$	0.8
Junction and storage temperature range	$T_J, T_{STG}$	-55 to 150	$^\circ\text{C}$

Parameter	Symbol	Typ	Max	Units
Maximum junction-ambient <sup>a</sup>	$R_{thJA}$	-	100	$^\circ\text{C/W}$
		130	-	

### Notes

- a. Surface mounted on FR4 board,
- b.  $t \leq 5$  sec.

#### 4. Electrical characteristics

(T<sub>A</sub>=25°C, unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
<b>Static</b>						
Drain-source breakdown voltage	V <sub>(BR)DSS</sub>	V <sub>DS</sub> =0V, I <sub>D</sub> =250μA	30	-	-	V
Gate threshold voltage	V <sub>GS(th)</sub>	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1	-	1.8	V
Gate- body leakage	I <sub>GSS</sub>	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
Zero gate voltage drain current	I <sub>DSS</sub>	V <sub>DS</sub> =25V, V <sub>GS</sub> =0V	-	-	1	μA
On-state drain current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> ≥4.5V, V <sub>GS</sub> =10V	6	-	-	A
		V <sub>DS</sub> ≥4.5V, V <sub>GS</sub> =4.5V	4	-	-	
Static drain-source on-resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =3.5A	-	-	0.057	Ω
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =2.8A	-	-	0.094	
Forward transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> =4.5V, I <sub>D</sub> =-3.5A	-	6.9	-	S
Diode forward voltage	V <sub>SD</sub>	V <sub>GS</sub> =0V, I <sub>S</sub> =1.25A	-	0.8	1.2	V
<b>Dynamic<sup>b</sup></b>						
Total gate charge	Q <sub>g</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =5V, I <sub>D</sub> =3.5A	-	4.2	7	nC
Total gate charge	Q <sub>gt</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =10V I <sub>D</sub> =3.5A	-	8.5	20	
Gate-source charge	Q <sub>gs</sub>		-	1.9	-	
Gate-drain charge	Q <sub>gd</sub>		-	1.35	-	
Gate resistance	R <sub>G</sub>		0.5	-	2.4	Ω
Input capacitance	C <sub>iss</sub>	V <sub>DS</sub> =15V, V <sub>GS</sub> =0V, f=1MHz	-	555	-	pF
Output capacitance	C <sub>oss</sub>		-	120	-	
Reverse transfer capacitance	C <sub>rss</sub>		-	60	-	
<b>Switching</b>						
Turn-on delay time	t <sub>d(on)</sub>	V <sub>DD</sub> =15V, I <sub>D</sub> =1A, R <sub>L</sub> =15Ω, R <sub>G</sub> =6Ω, V <sub>GEN</sub> =10V	-	9	20	ns
Rise time	t <sub>r</sub>		-	7.5	18	
Turn-off delay time	t <sub>d(off)</sub>		-	17	35	
Fall time	t <sub>f</sub>		-	5.2	12	

**Notes**

- a. Guaranteed by design, not subject to production testing.
- b. Pulse test; pulse width ≤ 300μs, duty cycle ≤ 2%.

**5. Test circuits and waveforms**

